

Process Change Notice

Parts Affected:

Chip process CPD64, Low Leakage Diode discrete semiconductors, wafers, and die in chip form.

Extent of Change:

The overall wafer diameter is being increased from 4 inch to 5 inch.
The overall die thickness is being reduced from 8 mils to 5.9 mils

Reason for Change:

Process transfer from the 4" wafer fab to the 5" wafer fab.

Effect of Change:

This change does not affect the electrical characteristics of any device.

Effective Date of Change:

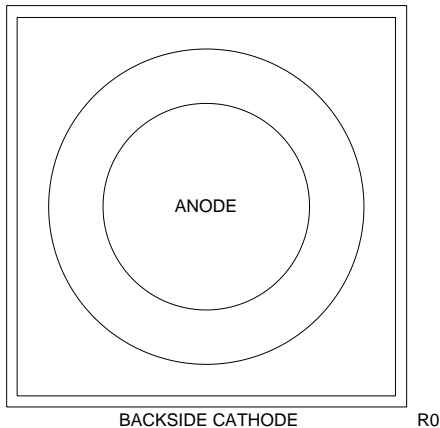
Existing inventory will be shipped until depleted.

Sample Availability:

Please contact Salesperson or Manufacturer's Representative.

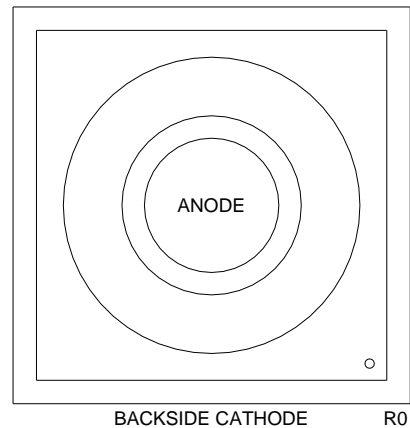
Figures:

Figure 1: CPD64 Chip Geometry



Die Size:	17.5 x 17.5 mils
Die Thickness:	8.0 mils
Bond Pad Area (Anode):	8.0 mils diameter
Topside Metal:	Al (30,000Å)
Backside Metal:	Au (6,000Å)
Gross Die per 4" wafer:	34,368

Figure 2: CPD66X Chip Geometry



Die Size:	17.5 x 17.5 mils
Die Thickness:	5.9 mils
Bond Pad Area (Anode):	8.0 mils diameter
Topside Metal:	Al (30,000Å)
Backside Metal:	Au-As (13,000Å)
Gross Die per 5" wafer:	54,848



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PCN # 110

Notification Date:

21 April 2009

Part Numbers Affected:

CPD64-CLL459A-CT
CPD64-CMPD3003-CT
CPD64-CMPD3003-WN
CPD64-1N3595-CT
CPD64-1N3595-WN
CPD64-1N3595-WR
CPD64-1N457A-CT
CPD64-1N485B-CT

CMDD3003
CMLD3003DOG
CMOD3003
CMPD3003
CMPD3003A
CMPD3003C
CMPD3003S
CMHD457A
CMHD459A
CMHD3595